



FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. <b>03500.015727.1</b>	APPLICATION NO. <b>10/799,859</b>				
			APPLICANT <b>TAKEO TSUKAMOTO</b>					
			FILING DATE <b>MARCH 15, 2004</b>	GROUP <b>2821</b>				
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>Amit</i>		2003/0222560	12/03	Roach	313	311		
<i>Amit</i>		2003/0048057	03/03	Kazunari et al.	313	311		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
<i>Amit</i>		09-237565	09/09/97	JAPAN	H01J	1/30	Abstract	
<i>Amit</i>		2000-191302	7/11/00	JAPAN	C01B	3/00	Abstract	
<i>Amit</i>		2000-277003	10/6/00	JAPAN	H01J	9/02	Abstract USP 2002/0136896 A1	
<i>Amit</i>		2001-052598	2/23/01	JAPAN	H01J	1/316	Abstract	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER	<i>Anne M. D. S.</i>							
		DATE CONSIDERED <b>2-8-06</b>						

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Sheet 1 of 1

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PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)ATTY DOCKET NO.  
**03500.015727.1**APPLICATION NO.  
**NYA**

APPLICANT

**TAKEO TSUKAMOTO**

FILING DATE

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GROUP

**2879  
2821**

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>AMT</i>	<b>2001/0006232 A1</b>	<b>7/01</b>	<b>Choi et al.</b>			

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	<b>04-212236</b>	<b>03/08/92</b>	<b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>No</b>
	<b>03-295131</b>	<b>12/26/91</b>	<b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>No</b>
	<b>A2 535 953</b>	<b>04/07/93</b>	<b>EPO</b>	<b>H01J</b>	<b>1/30</b>	<b>English</b>
	<b>05-159696</b>	<b>06/25/93</b>	<i>DUPLICATE</i> <b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>No</b>
	<b>05-198253</b>	<b>08/06/93</b>	<i>DUPLICATE</i> <b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>No</b>
	<b>05-274997</b>	<b>10/22/93</b>	<b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>Abst.</b>
	<b>11-232997</b>	<b>08/27/99</b>	<b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>No</b>
	<b>A1 936 650</b>	<b>08/18/99</b>	<b>EPO</b>	<b>H01J</b>	<b>3/02</b>	<b>English</b>
	<b>10-289650</b>	<b>10/27/98</b>	<b>Japan</b>	<b>H01J</b>	<b>1/30</b>	<b>No</b>
	<b>A1 871 195</b>	<b>10/14/98</b>	<b>EPO</b>	<b>H01J</b>	<b>1/30</b>	<b>English</b>

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	<b>M. Hartwell et al., "Strong Electron Emission from Patterned Tin-Indium Oxide Thin Films", IEEE Trans. Ed. Conf., (1983) pp.519-521</b>
	<b>Hisashi Araki et al., "Electroforming and Electron Emission of Carbon Thin Films, Journal of the Vacuum Society of Japan, 1983 (with English Abstract on p. 22)</b>
	<b>Rodriguez et al., "Catalytic Engineering of Carbon Nanostructures," Langmuir 11, 3862-3866 (1995).</b>

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Sheet 7 of 12

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	2002/0031972	3/02	Kitamura et al.	445	3	
	6,400,091	6/02	Deguchi et al.	315	169.1	
	6,420,726	7/02	Choi et al.	257	10	

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	0 980 089 A1	02/16/00	EPO	H01J	1/30	English
	0 986 084 A2	03/15/00	EPO	H01J	1/30	English
	1 117 118 A1	07/08/01	EPO	H01J	1/312	English
	0 716 439	06/12/96	EPO	H01J	3/02	English
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	2-112125	04/24/90	JAPAN	H01J	1/30	Abst. & corresponding U.S. Patent 4,956,578

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	H. Dai et al., "Single-Wall Nanotubes Produced by Metal-Catalyzed Disproportionation of Carbon Monoxide," <i>Chem. Phys. Lett.</i> , Vol. 260, 471-475 (1996).
<i>Annt</i>	H. Dai et al., "Nanotubes as Nanoprobes in Scanning Probe Microscopy," <i>Nature</i> , Vol. 384, 147-150 (1996).
	A. C. Dillon et al., "Storage of Hydrogen in Single-Walled Carbon Nanotubes," <i>Nature</i> , Vol. 386, 377-379 (1997).
	W.P. Dyke et al., "Field Emission," <i>Advances in Electronics and Electron Physics</i> , Vol. 8, (1956) pp. 89-185
	C.A. Spindt et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones," <i>Journal of Applied Physics</i> , Vol. 47, No. 12 (1976), pp. 5248-5263

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2/8/04

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